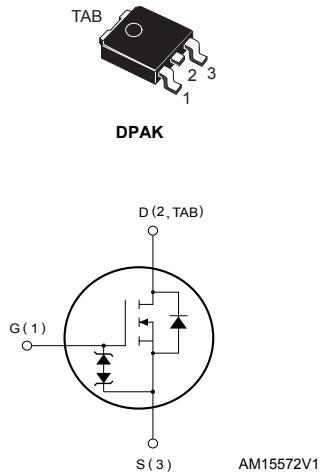


## N-channel 800 V, 730 mΩ typ., 7 A MDmesh K5 Power MOSFET in a DPAK package

### Features



Order code	V <sub>DS</sub>	R <sub>DS(on)max.</sub>	I <sub>D</sub>	P <sub>TOT</sub>
STD9N80K5	800 V	900 mΩ	7 A	110 W

- Industry's lowest R<sub>DS(on)</sub> x area
- Industry's best figure of merit (FoM)
- Ultra-low gate charge
- 100% avalanche tested
- Zener-protected

### Applications

- Switching applications

### Description

This very high voltage N-channel Power MOSFET is designed using MDmesh K5 technology based on an innovative proprietary vertical structure. The result is a dramatic reduction in on-resistance and ultra-low gate charge for applications requiring superior power density and high efficiency.



#### Product status link

[STD9N80K5](#)

#### Product summary

Order code	STD9N80K5
Marking	9N80K5
Package	DPAK
Packing	Tape and reel

## 1 Electrical ratings

**Table 1. Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{GS}$	Gate-source voltage	$\pm 30$	V
$I_D$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	7	A
$I_D$	Drain current (continuous) at $T_C = 100^\circ\text{C}$	4.4	A
$I_{DM}^{(1)}$	Drain current (pulsed)	28	A
$P_{TOT}$	Total power dissipation at $T_C = 25^\circ\text{C}$	110	W
$dv/dt^{(2)}$	Peak diode recovery voltage slope	4.5	V/ns
$dv/dt^{(3)}$	MOSFET dv/dt ruggedness	50	V/ns
$T_{stg}$	Storage temperature range	- 55 to 150	$^\circ\text{C}$
$T_j$	Operating junction temperature range		

1. Pulse width limited by safe operating area.
2.  $I_{SD} \leq 7 \text{ A}$ ,  $di/dt \leq 100 \text{ A}/\mu\text{s}$ ;  $V_{DS}$  peak <  $V_{(BR)DSS}$ ;  $V_{DD} = 640 \text{ V}$
3.  $V_{DS} \leq 640 \text{ V}$

**Table 2. Thermal data**

Symbol	Parameter	Value	Unit
$R_{thJC}$	Thermal resistance, junction-to-case	1.14	$^\circ\text{C}/\text{W}$
$R_{thJA}^{(1)}$	Thermal resistance, junction-to-ambient	50	$^\circ\text{C}/\text{W}$

1. When mounted on FR-4 board of 1 inch<sup>2</sup>, 2 oz Cu

**Table 3. Avalanche characteristics**

Symbol	Parameter	Value	Unit
$I_{AR}$	Avalanche current, repetitive or not repetitive (pulse width limited by $T_{jmax}$ )	2.4	A
$E_{AS}$	Single pulse avalanche energy (starting $T_j = 25^\circ\text{C}$ , $I_D = I_{AR}$ ; $V_{DD} = 50 \text{ V}$ )	200	mJ

## 2 Electrical characteristics

$T_C = 25^\circ\text{C}$  unless otherwise specified.

**Table 4. On/off states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	800			V
$I_{\text{DSS}}$	Zero gate voltage Drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 800 \text{ V}$			1	$\mu\text{A}$
		$V_{GS} = 0 \text{ V}, V_{DS} = 800 \text{ V}, T_C = 125^\circ\text{C}$			50	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			$\pm 10$	$\mu\text{A}$
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 100 \mu\text{A}$	3	4	5	V
$R_{\text{DS(on)}}$	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}, I_D = 3.5 \text{ A}$		730	900	$\text{m}\Omega$

1. Specified by design, not tested in production.

**Table 5. Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{DS} = 100 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$	-	340	-	pF
$C_{oss}$	Output capacitance		-	37	-	pF
$C_{rss}$	Reverse transfer capacitance		-	0.65	-	pF
$C_{o(tr)}^{(1)}$	Equivalent capacitance time related	$V_{DS} = 0 \text{ to } 640 \text{ V}, V_{GS} = 0 \text{ V}$	-	61	-	pF
$C_{o(er)}^{(2)}$	Equivalent capacitance energy related		-	22	-	pF
$R_g$	Intrinsic gate resistance	$f = 1 \text{ MHz}, I_D = 0 \text{ A}$	-	7	-	$\Omega$
$Q_g$	Total gate charge	$V_{DD} = 640 \text{ V}, I_D = 7 \text{ A}$ $V_{GS} = 0 \text{ to } 10 \text{ V}$ See (Figure 15. Test circuit for gate charge behavior)	-	12	-	nC
$Q_{gs}$	Gate-source charge		-	3.8	-	nC
$Q_{gd}$	Gate-drain charge		-	6.7	-	nC

- $C_{o(tr)}$  is a constant capacitance value that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .
- $C_{o(er)}$  is a constant capacitance value that gives the same stored energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$

**Table 6. Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 400 \text{ V}, I_D = 3.5 \text{ A}$ $R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ See (Figure 14. Test circuit for resistive load switching times and Figure 19. Switching time waveform)	-	11	-	ns
$t_r$	Rise time		-	5.7	-	ns
$t_{d(off)}$	Turn-off delay time		-	65.3	-	ns
$t_f$	Fall time		-	13.6	-	ns

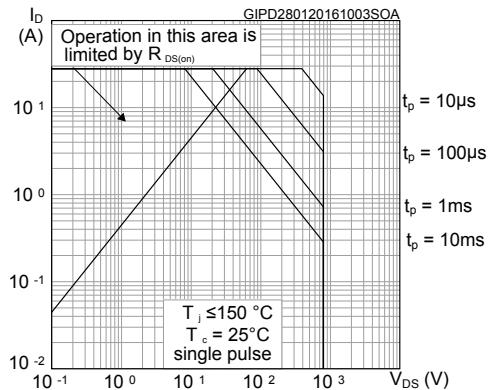
Table 7. Source-drain diode

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}$	Source-drain current		-		7	A
$I_{SDM}$ <sup>(1)</sup>	Source-drain current (pulsed)		-		28	A
$V_{SD}$ <sup>(2)</sup>	Forward on voltage	$I_{SD} = 7 \text{ A}, V_{GS} = 0 \text{ V}$	-		1.5	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 7 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}, V_{DD} = 60 \text{ V}$	-	292		ns
$Q_{rr}$	Reverse recovery charge	See Figure 16. Test circuit for inductive load switching and diode recovery times	-	2.66		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	18.2		A
$t_{rr}$	Reverse recovery time		-	477		ns
$Q_{rr}$	Reverse recovery charge	$V_{DD} = 60 \text{ V}, T_j = 150^\circ\text{C}$ See Figure 16. Test circuit for inductive load switching and diode recovery times	-	3.91		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	16.4		A

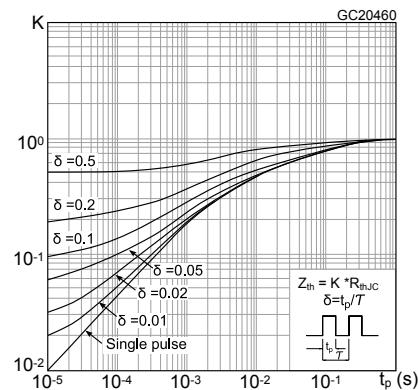
1. Pulse width limited by safe operating area
2. Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%

## 2.1 STD9N80K5\_Electrical characteristics curves

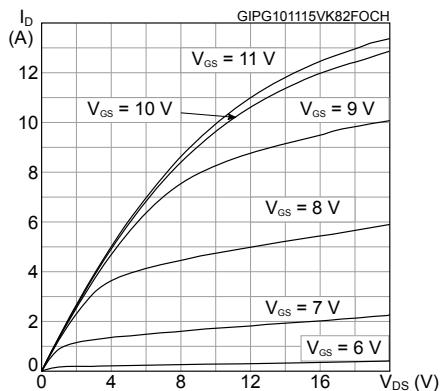
**Figure 1. Safe operating area**



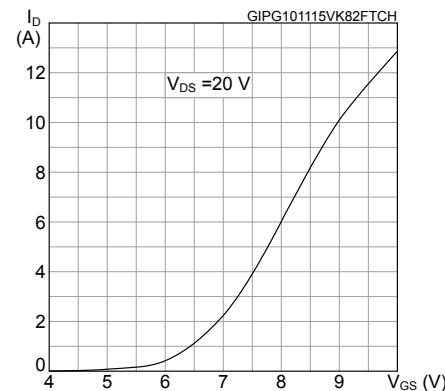
**Figure 2. Thermal impedance**



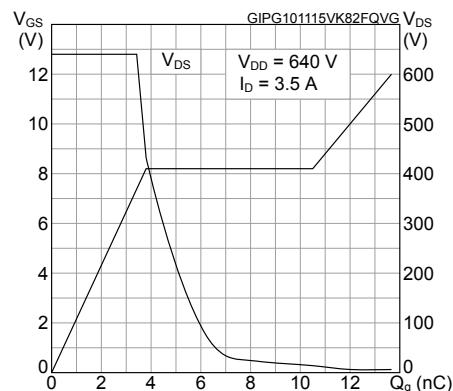
**Figure 3. Output characteristics**



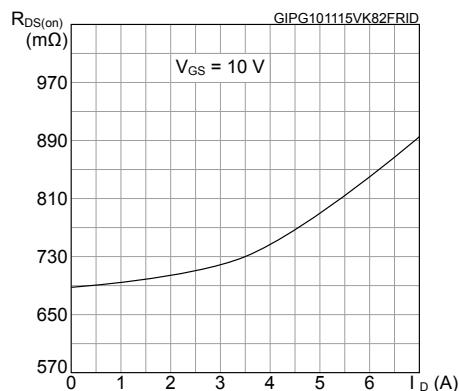
**Figure 4. Transfer characteristics**

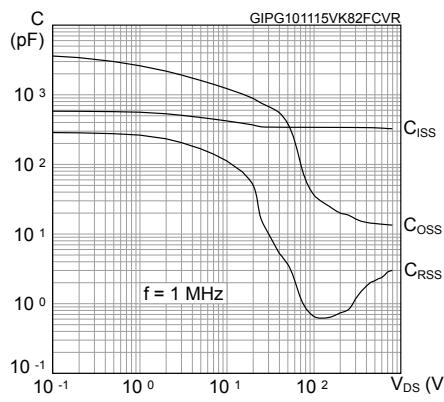
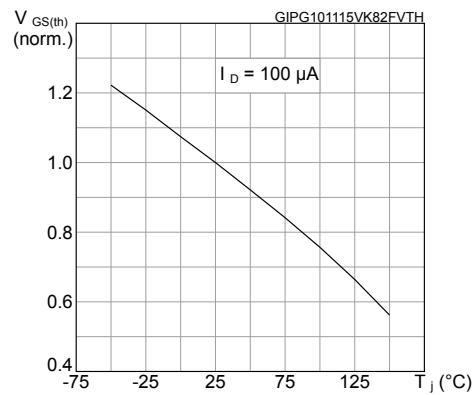
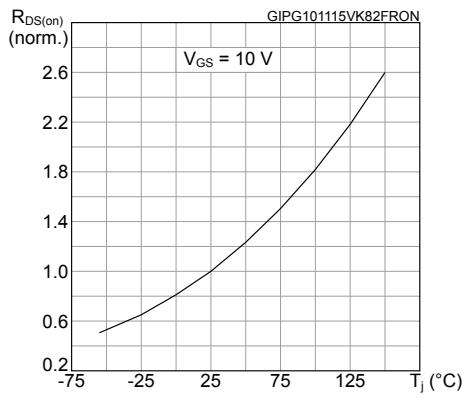
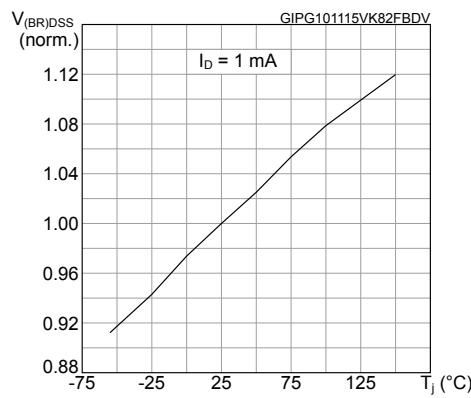
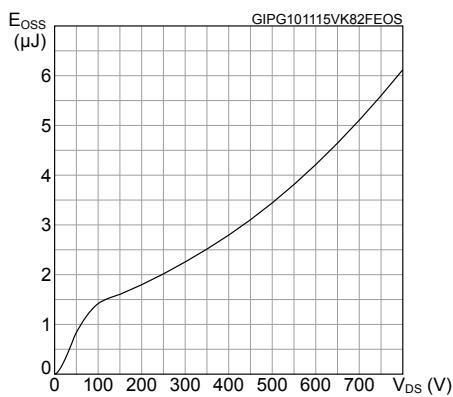
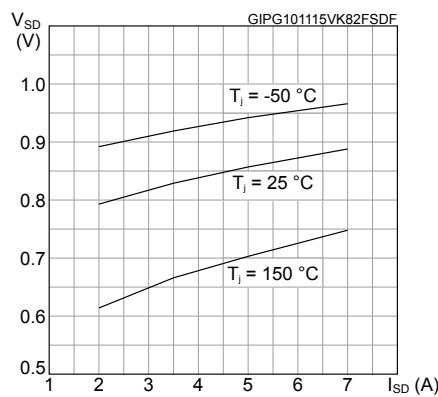


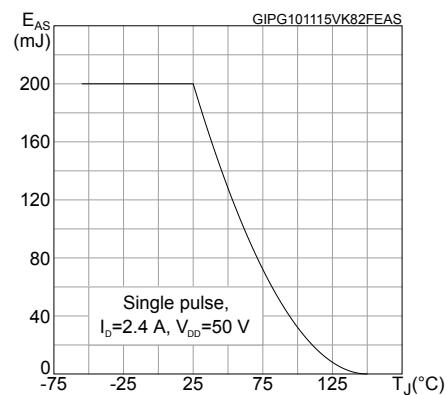
**Figure 5. Gate charge vs gate-source voltage**



**Figure 6. Static drain-source on-resistance**

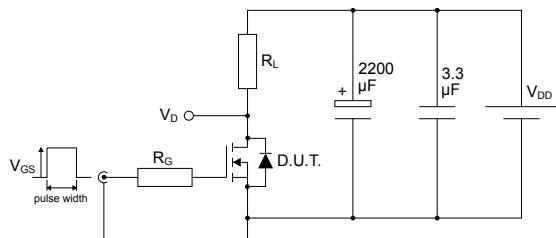


**Figure 7. Capacitance variations**

**Figure 8. Normalized gate threshold voltage vs temperature**

**Figure 9. Normalized on-resistance vs temperature**

**Figure 10. Normalized  $V_{(BR)DSS}$  vs temperature**

**Figure 11. Output capacitance stored energy**

**Figure 12. Source-drain diode forward characteristics**


**Figure 13. Maximum avalanche energy vs starting  $T_J$** 

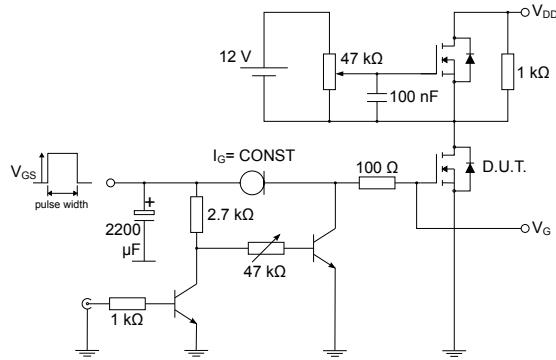
### 3 Test circuits

**Figure 14.** Test circuit for resistive load switching times



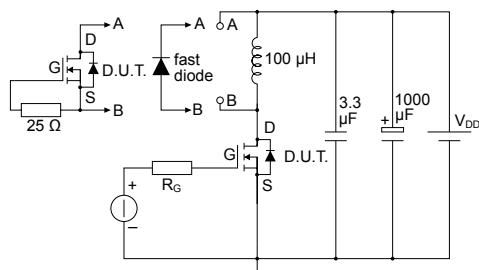
AM01468v1

**Figure 15.** Test circuit for gate charge behavior



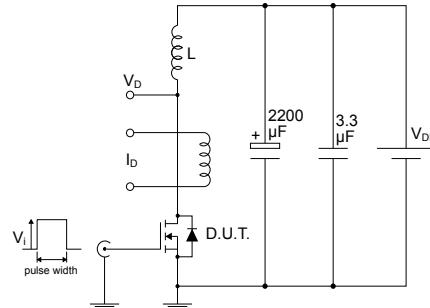
AM01469v1

**Figure 16.** Test circuit for inductive load switching and diode recovery times



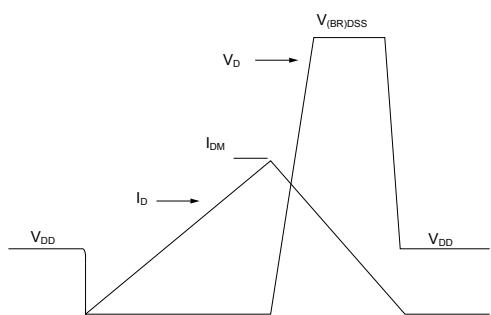
AM01470v1

**Figure 17.** Unclamped inductive load test circuit



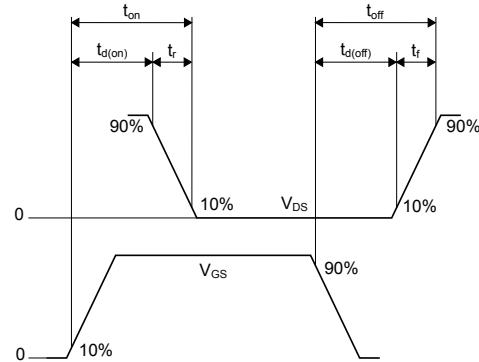
AM01471v1

**Figure 18.** Unclamped inductive waveform



AM01472v1

**Figure 19.** Switching time waveform



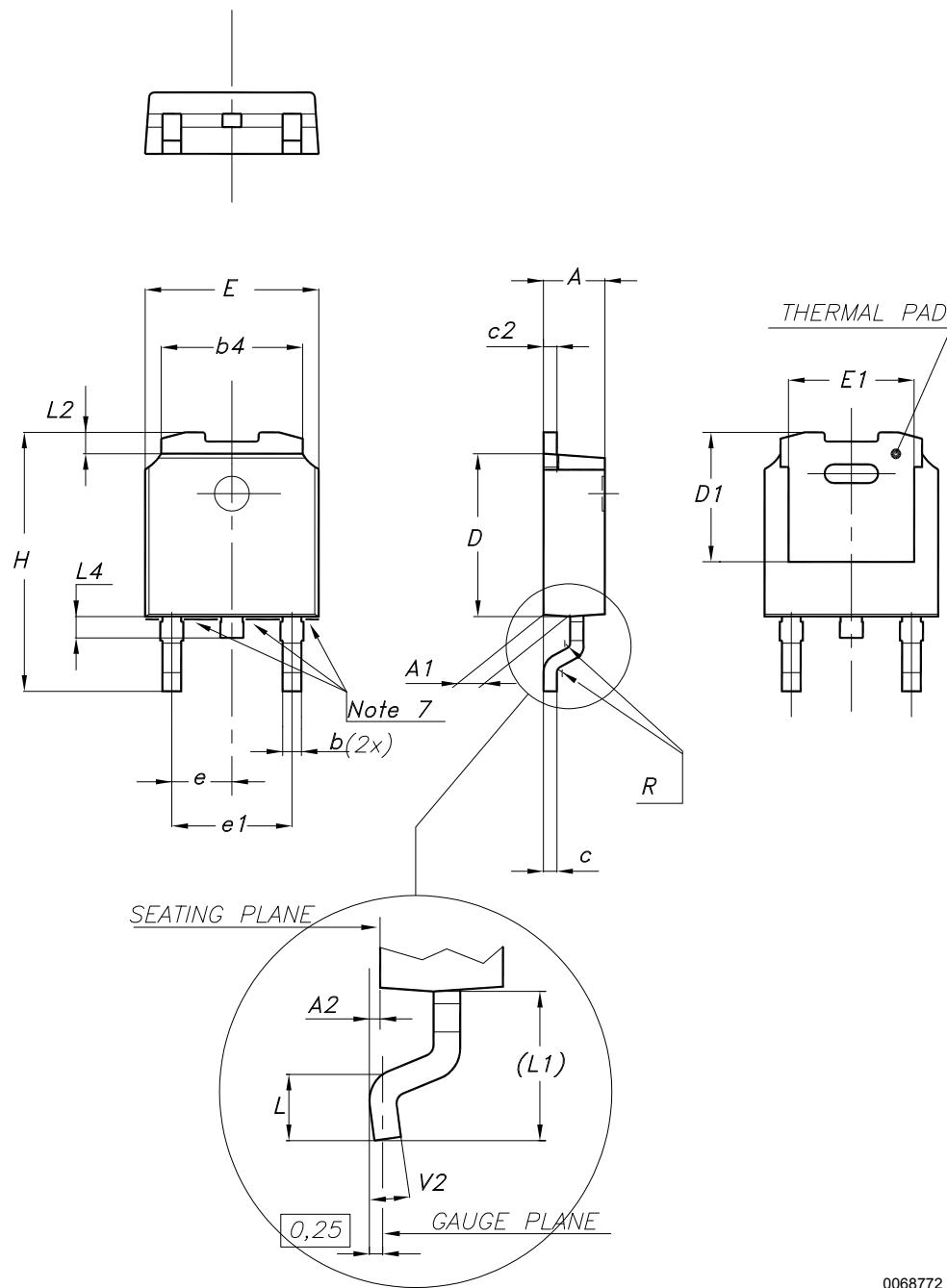
AM01473v1

## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com). ECOPACK is an ST trademark.

### 4.1 DPAK (TO-252) type A2 package information

Figure 20. DPAK (TO-252) type A2 package outline



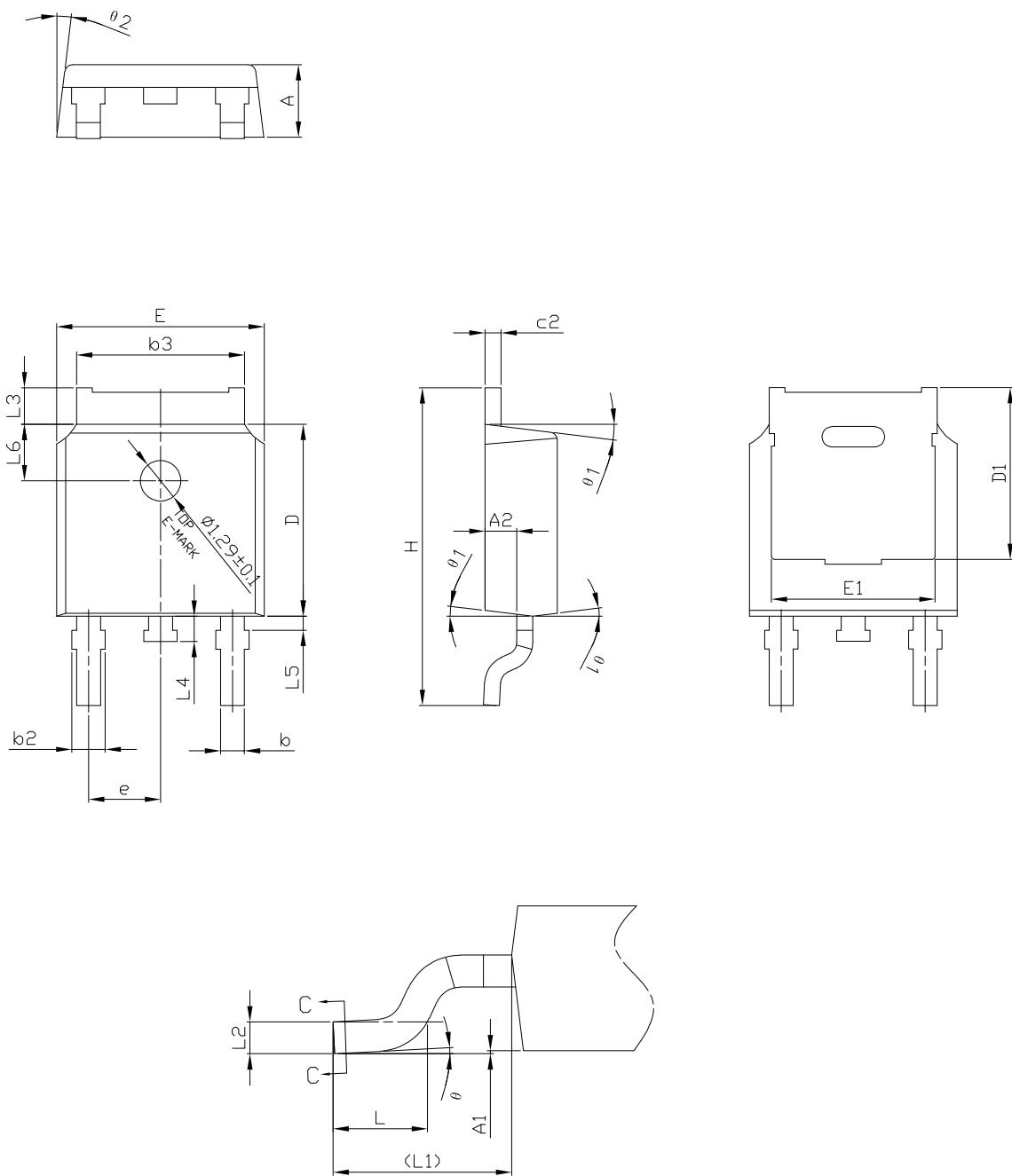
0068772\_type-A2\_rev34

Table 8. DPAK (TO-252) type A2 mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	2.20		2.40
A1	0.90		1.10
A2	0.03		0.23
b	0.64		0.90
b4	5.20		5.40
c	0.45		0.60
c2	0.48		0.60
D	6.00		6.20
D1	4.95	5.10	5.25
E	6.40		6.60
E1	5.10	5.20	5.30
e	2.159	2.286	2.413
e1	4.445	4.572	4.699
H	9.35		10.10
L	1.00		1.50
L1	2.60	2.80	3.00
L2	0.65	0.80	0.95
L4	0.60		1.00
R		0.20	
V2	0°		8°

## 4.2 DPAK (TO-252) type C3 package information

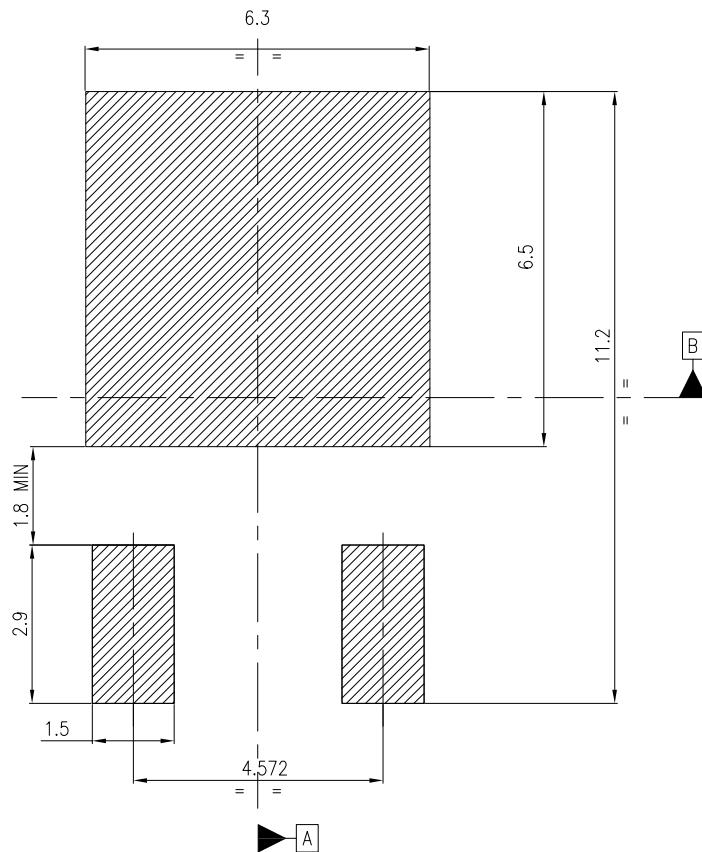
Figure 21. DPAK (TO-252) type C3 package outline



0068772\_type-C3\_rev34

Table 9. DPAK (TO-252) type C3 mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	2.20	2.30	2.38
A1	0.00		0.10
A2	0.90	1.01	1.10
b	0.72		0.85
b2	0.72		1.10
b3	5.13	5.33	5.46
c	0.47		0.60
c2	0.47		0.60
D	6.00	6.10	6.20
D1	5.20	5.45	5.70
E	6.50	6.60	6.70
E1	5.00	5.20	5.40
e	2.186	2.286	2.386
H	9.80	10.10	10.40
L	1.40	1.50	1.70
L1	2.90 REF		
L2	0.51 BSC		
L3	0.90		1.25
L4	0.60	0.80	1.00
L5	0.15		0.75
L6	1.80 REF		
θ	0°		8°
θ1	5°	7°	9°
θ2	5°	7°	9°

**Figure 22. DPAK (TO-252) recommended footprint (dimensions are in mm)**

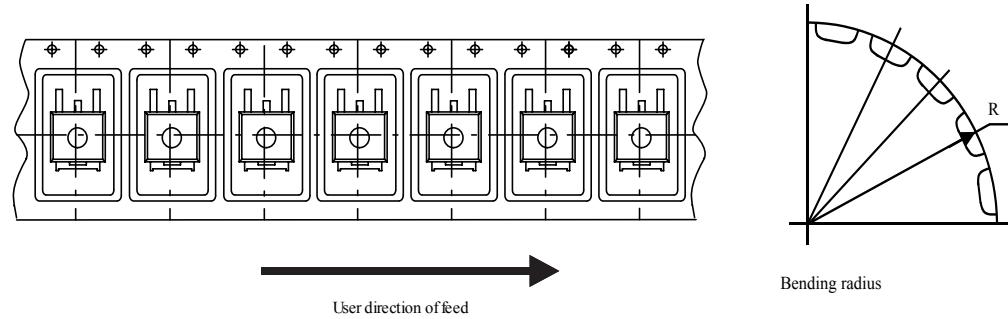
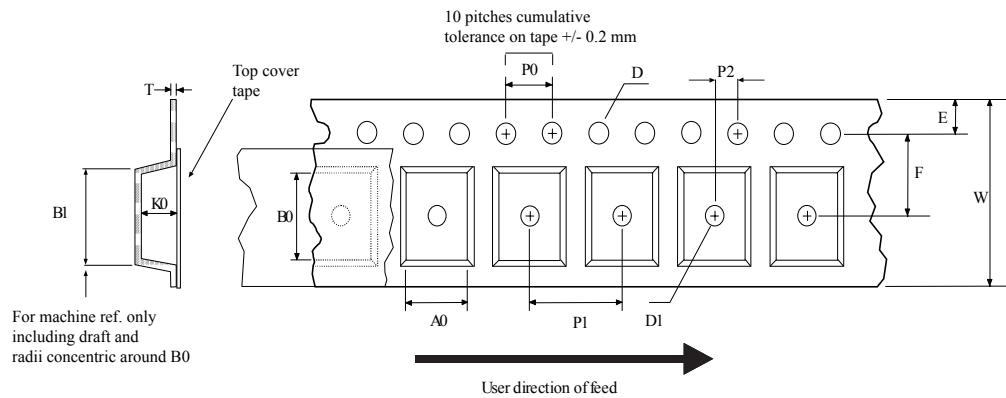
## Notes:

- 1) This footprint is able to ensure insulation up to 630 Vrms (according to CEI IEC 664-1)
- 2) The device must be positioned within  $\Phi | 0.05 | A | B$

FP\_0068772\_34

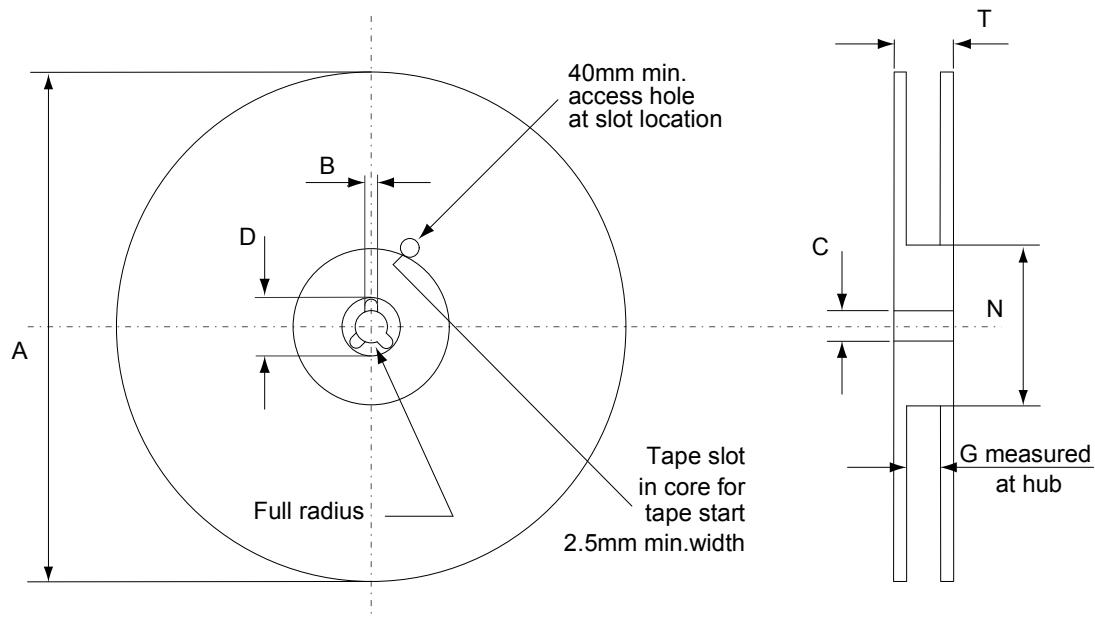
## 4.3 DPAK (TO-252) packing information

**Figure 23. DPAK (TO-252) tape outline**



AM08852v1

Figure 24. DPAK (TO-252) reel outline



AM06038v1

Table 10. DPAK (TO-252) tape and reel mechanical data

Tape			Reel		
Dim.	mm		Dim.	mm	
	Min.	Max.		Min.	Max.
A0	6.8	7	A		330
B0	10.4	10.6	B	1.5	
B1		12.1	C	12.8	13.2
D	1.5	1.6	D	20.2	
D1	1.5		G	16.4	18.4
E	1.65	1.85	N	50	
F	7.4	7.6	T		22.4
K0	2.55	2.75			
P0	3.9	4.1	Base qty.		2500
P1	7.9	8.1	Bulk qty.		2500
P2	1.9	2.1			
R	40				
T	0.25	0.35			
W	15.7	16.3			

## Revision history

**Table 11. Document revision history**

Date	Revision	Changes
20-Oct-2015	1	First release.
28-Jan-2016	2	Document status promoted from preliminary to production data. Updated DPAK (TO-252) type A2 package information. Inserted <a href="#">Section 2 Electrical characteristics</a> . Minor text changes.
12-Nov-2018	3	Updated <a href="#">Table 5. Dynamic</a> and <a href="#">Table 7. Source-drain diode</a> . Added <a href="#">Section 4.2 DPAK (TO-252) type C2 package information</a> .
15-May-2023	4	Updated <a href="#">Section 4.1 DPAK (TO-252) type A2 package information</a> . Added <a href="#">Section 4.2 DPAK (TO-252) type C3 package information</a> . Minor text changes.

## Contents

<b>1</b>	<b>Electrical ratings .....</b>	<b>2</b>
<b>2</b>	<b>Electrical characteristics.....</b>	<b>3</b>
<b>2.1</b>	STD9N80K5_Electrical characteristics curves .....	5
<b>3</b>	<b>Test circuits .....</b>	<b>8</b>
<b>4</b>	<b>Package information.....</b>	<b>9</b>
<b>4.1</b>	DPAK (TO-252) type A2 package information .....	9
<b>4.2</b>	DPAK (TO-252) type C3 package information.....	11
<b>4.3</b>	DPAK (TO-252) packing information.....	14
	<b>Revision history .....</b>	<b>16</b>

**IMPORTANT NOTICE – READ CAREFULLY**

STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, enhancements, modifications, and improvements to ST products and/or to this document at any time without notice. Purchasers should obtain the latest relevant information on ST products before placing orders. ST products are sold pursuant to ST's terms and conditions of sale in place at the time of order acknowledgment.

Purchasers are solely responsible for the choice, selection, and use of ST products and ST assumes no liability for application assistance or the design of purchasers' products.

No license, express or implied, to any intellectual property right is granted by ST herein.

Resale of ST products with provisions different from the information set forth herein shall void any warranty granted by ST for such product.

ST and the ST logo are trademarks of ST. For additional information about ST trademarks, refer to [www.st.com/trademarks](http://www.st.com/trademarks). All other product or service names are the property of their respective owners.

Information in this document supersedes and replaces information previously supplied in any prior versions of this document.

© 2023 STMicroelectronics – All rights reserved